

August 25, 2006

Supplement to HAC Test Report for Motorola portable cellular phone (IHDT56FT1)

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There was a request for additional information regarding Motorola's HAC Test Reports for Motorola portable cellular phone (FCC ID IHDT56FT1). The requested information is addressed below in the same numbering sequence received.

1.

Appendix 3-6 (Page 26) states a CMU200 manual reference value was used for the calculation of the 0dBm0 reference whereas Exhibit 6B-2 (Page 7) states that an internal calibration procedure should be implemented. Please show that the vocoder calibration was performed and was correctly implemented for the testing.

RESPONSE:

To calculate "0dBm0 Input reference", we use both "CMU200 manual reference value" and "Input Correction Factor". "Input Correction Factor" is measured using internal procedure described in 3-5.

2.

Please justify use of the RF frequency chosen. Please include a demonstration that ABM2 noise is not affected by RF frequency or that the frequency chosen is worst-case. Alternatively, submit data for the low and high channels.

RESPONSE:

We have carried out ABM2 (phone noise) investigation to determine the highest channel / frequency for ABM2. In achieve this, ABM2 is measured at the location of the T-coil source. For each band, the channel with the highest ABM2 measurement is highlighted in **bold**. For CDMA 800 band, the highest ABM2 measurement has occurred on Ch 384. For CDMA 1900 band, the highest ABM2 measurement has occurred on Ch 600.

**ABM2 measurements across the frequency band
for the portable cellular telephone at highest possible output power.**

ABM2 Measurements (dB A/m)		
CDMA 800	Ch 1013	- 47.69
	Ch 384	- 47.05
	Ch 777	- 48.33
CDMA 1900	Ch 25	- 47.35
	Ch 600	- 46.64
	Ch 1175	- 47.76

3.

Please indicate whether backlight was on or off during test conditions in Table 4. If off, then HAC compliance operation should be explained in the Users Manual.

RESPONSE:

Backlight was off during testing. HAC compliance will be explained in the manual.

4.

ABM2 figure reference in Appendix 3-1 (Page 21) was not found. Please supply. Please show that significant audio band noise components beyond 10kHz were addressed.

RESPONSE:

Speag's software does not allow the user to display results beyond 5kHz. Please note that the calculations use time domain operation, not frequency domain operation. Therefore, although it is not obvious in the plots provided in Appendix 1 of "HAC Test Report for T-coil IHDT56FT1" from July 18, 2006, the results are based on the entire frequency range of the signal (with sampling frequency of 48 kHz). The attached report from SPEAG, "T-Coil probe linearity and Frequency Response", addresses this topic in depth.

5.

Please provide details of the measurement from device reference plane to probe for the Clause 6 tests.

RESPONSE:

The distance is established by positioning the device beneath the test arch phantom so that it is touching the frame. The location and thickness of the arch, and the location/orientation of the coil within the probe housing, are precisely known values in the DASY software. The height of the measurement plane is further fine-tuned by performing a Surface Detection job at the beginning of each test. The end result is that the probe sensor is very precisely located 10mm above the device reference plane.

6.

Please show that the vocoder can pass the 1kHz 1/3 octave banded signal.

RESPONSE:

The 1kHz narrowband signal was measured with a Bruel & Kjaar 2144 to be -18.8dB V. The same signal was then passed through the Encode / Decode processes of the CMU200, and re-measurement with the Bruel & Kjaar resulted in -18.9dB V.

7.

Please fully address the FCC 3G policy recently issued in June 2006. Please provide details of device capability, RF modes and vocoder modes/options used. Please also provide S02 and S055 conducted powers as required in the 3G guidance in RF emissions report.

RESPONSE:

S02 conducted power measurements (dBm):

	S02		
	Channel	RC1	RC2
800CDMA	1013	24.81	24.75
	384	24.97	24.86
	777	24.91	24.95
1900CDMA	25	24.66	24.66
	600	24.76	24.82
	1175	24.72	24.75

S055 conducted power measurements:

Per the "Preliminary Guidance for Reviewing Applications for Certifications of 3G Devices" released on May 9, 2006, both RC1 and RC3 CDMA modes are considered (steps 3 & 4 of section 4.4.5.2 of 3GPP2 C.5.011 / TIA -98-E). The conducted power measurements show that the portable cellular phone FCC ID IHDT56FT1 has the same output conducted power for both CDMA modes.

Conducted Output Power (dBm):

CDMA 800	RC1	RC3
CH 1013	24.9 dBm	24.9 dBm
CH 384	25.0 dBm	25.0 dBm
CH 777	25.0 dBm	25.0 dBm
CDMA 1900	RC1	RC3
CH 25	24.8 dBm	24.7 dBm
CH 600	24.9 dBm	24.9 dBm
CH 1175	24.8 dBm	24.8 dBm

8.

Please discuss uncertainty table items. Which are lab specific? Please be sure to include Noise Contribution, RF interference and DUT positioning in your response.

RESPONSE:

Noise Contribution: The specific noise levels measured in our lab at the time of these tests are significantly lower than the "typical worst case noise levels" that were used by SPEAG to establish the 0.7% uncertainty component. Our reported 1kHz noise levels are below -67 dB A/m, compared to SPEAG's stated -55 dB A/m. And our reported 300-3000Hz noise levels are below -57 dB A/m, compared to SPEAG's stated -48 dB A/m. Therefore, the uncertainty component of 0.7% adequately covers our current and foreseeable noise contributions.

RF Interference: The SPEAG HAC T-Coil Extension uses a fully RF shielded probe. Contribution to the uncertainty budget is negligible.

DUT Positioning: The attached table has been updated to account for lab repeat measurements of a reference unit.

HAC T-Coil Uncertainty Budget

Error Description	Uncertainty value (%)	Prob. Dist.	Div.	c ABM1	c ABM2	St.Unc ABM1 (%)	St.Unc ABM2 (%)
PROBE SENSITIVITY							
Reference level	3.0	N	1	1	1	3.0	3.0
AMCC geometry	0.4	R	1.7	1	1	0.2	0.2
AMCC current	0.6	R	1.7	1	1	0.4	0.4
Probe positioning during calibration	0.1	R	1.7	1	1	0.1	0.1
Noise contribution	0.7	R	1.7	0.0143	1	0.0	0.4
Frequency slope	5.9	R	1.7	0.1	1	0.3	3.5
PROBE SYSTEM							
Repeatability / Drift	1.0	R	1.7	1	1	0.6	0.6
Linearity / Dynamic range	0.6	R	1.7	1	1	0.4	0.4
Acoustic noise	1.0	R	1.7	0.1	1	0.1	0.6
Probe angle	2.3	R	1.7	1	1	1.4	1.4
Spectral processing	0.9	R	1.7	1	1	0.5	0.5
Integration time	0.6	N	1	1	5	0.6	3.0
Field disturbance	0.2	R	1.7	1	1	0.1	0.1
TEST SIGNAL							
Reference signal spectral response	0.6	R	1.7	0	1	0.0	0.4
POSITIONING							
Probe positioning	1.9	R	1.7	1	1	1.1	1.1
Phantom thickness	0.9	R	1.7	1	1	0.5	0.5
DUT positioning **	4.0	R	1.7	1	1	2.4	2.4
EXTERNAL CONTRIBUTIONS							
RF interference	0.0	R	1.7	1	1	0.0	0.0
Test signal variation	2.0	R	1.7	1	1	1.2	1.2
COMBINED UNCERTAINTY							
Combined Std.Uncert. (ABM field)						4.6	6.5
Expanded Std. Uncertainty, k=2 (%)						9.1	12.9

** based on repeat measurements of reference unit

9.

Please submit test setup photographs for ABM testing.

RESPONSE:

The device position is the same for ABM tests and RF tests.



10.

Please provide validation for use of 30 kHz VBW.

RESPONSE:

The power measurements were compared and verified using spectrum analyzer (VBW = 30 Hz) and average power meter.

FYI

In the future, please submit ABM noise spectrum plots to 10kHz

RESPONSE:

System users do not have the ability to display the plot you have requested. Please refer to question 4 above for explanation and technical justification."